

Product release: NuNano launches reliable high-performance probes for soft sample imaging

Bristol – 16 January, 2018 – NuNano are delighted to announce the release of the Scout 70 model of AFM probes, enabling our consistent tip sharpness and minimal variation of mechanical properties to be applied to high resolution imaging of soft samples.

The [Scout 70](#) is a general purpose silicon AFM probe for imaging in AC modes (non-contact/soft tapping) and force modulation, with a nominal 2N/m spring constant and 70 kHz resonant frequency, making it ideal for imaging delicate samples or objects that are loosely adhered to their substrate surface.

With two other variants, the Scout 70 is also available as [Scout 70 HAR](#) with a high aspect ratio tip for deep trench imaging. The [Scout 70 T](#), with its lower resolution tip, is perfect for step height measurements and getting new AFM users started. All probes are available either uncoated or with reflective aluminium coating on the backside of the cantilever.

“NuNano’s silicon AFM probes have remarkably consistent resonant frequencies and driving amplitude” said Dr Vladimir Korolkov, University of Nottingham. “This gives me confidence that I’ll acquire high quality images every time I use them.”

“Our new probe allows users to access a lower force regime whilst maintaining the same high standards of reliability you’ve come to expect from our [other products](#),” said Dr James Vicary, NuNano Co-founder & Managing Director.

“Applying our proprietary manufacturing process to our Scout 70 probes has meant we’ve been able achieve the same tight dimensional control of the cantilever, which in turn ensures there’s less variation in the mechanical properties of our probes.”

About Scout 70 AFM Probe Model

The Scout 70 model of AFM probes have been specifically developed to provide the same exemplary dimensional tolerances and tip sharpness characteristic of all [our AFM probes](#). Click on the links below for more detailed specifications and pricing:

- [Scout 70](#) - general purpose AC mode silicon AFM probes, suitable for non-contact/soft tapping and force modulation modes in air, on softer samples. **Spring constant:** 2 N/m. **Resonant frequency:** 70 kHz
- [Scout 70 HAR](#) – as above, but featuring a high aspect ratio tip with a cone angle over the last 1 µm of less than 15 degrees.
- [Scout 70 T](#) - a lower resolution version with a tip radius of between 10 - 40 nm, perfect for training new AFM users and for applications where price is more important than tip sharpness.

As with all NuNano products the Scout 70 model is compatible with most commercially available AFMs. For harder samples, including stable softer samples, our [Scout 350](#) model is also available.

For more information, to request a datasheet, free sample or a meeting with one of our team to discuss your needs further please call - +44 117 299 3093 or email info@nunano.com

About NuNano

NuNano is a UK-based company specialising in the design and manufacture of consistently high-performance probes for atomic force microscopy and cantilever-based sensor devices.